

Digital Microelectronic Circuits

(361-1-3021)

Presented by: Adam Teman

Lecture 12:

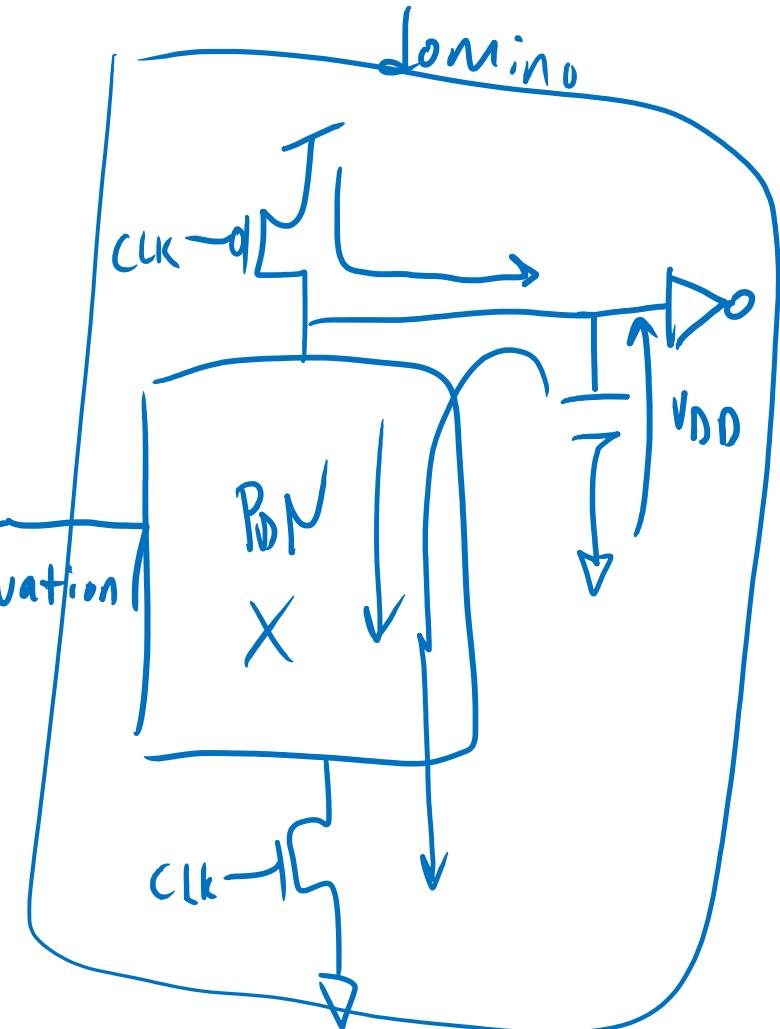
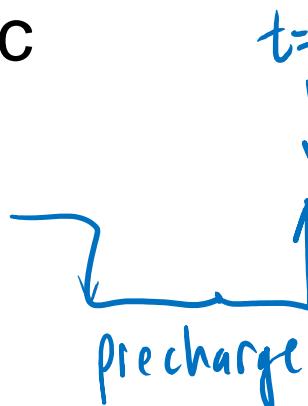
Sequential Logic Circuits and Memories



Last Lecture

□ Dynamic Logic

- » Features and Problems
- » Domino Logic



This Lecture

- An introduction to sequential circuits and semiconductor memory, focusing on the circuit level implementation of basic gates and cells.
- A much more in-depth study of these circuits will be given in Introduction to VLSI.

What will we learn today?

11.1 The Latch

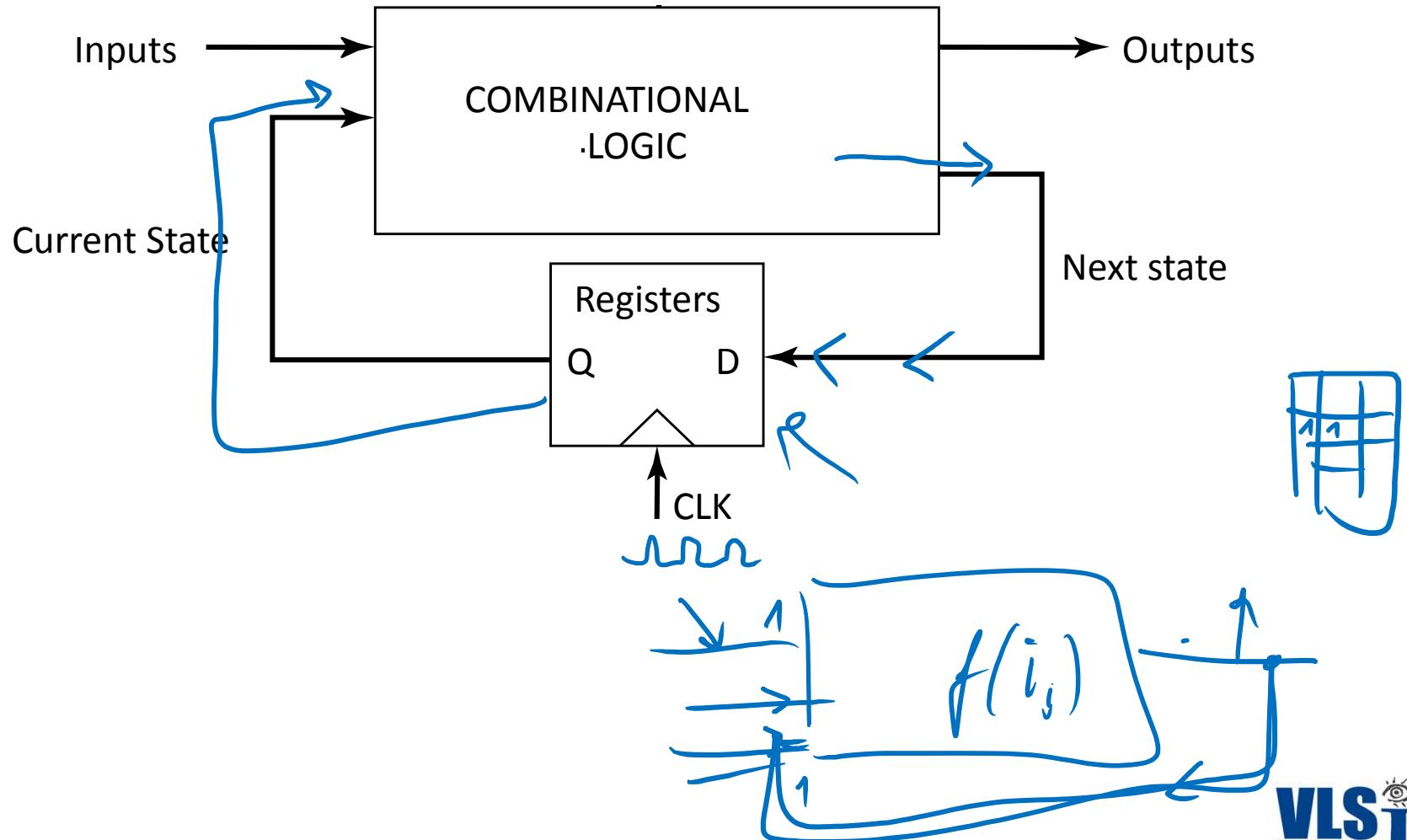
11.2 The Flip Flop

11.3 Read Only Memory

11.4 SRAM

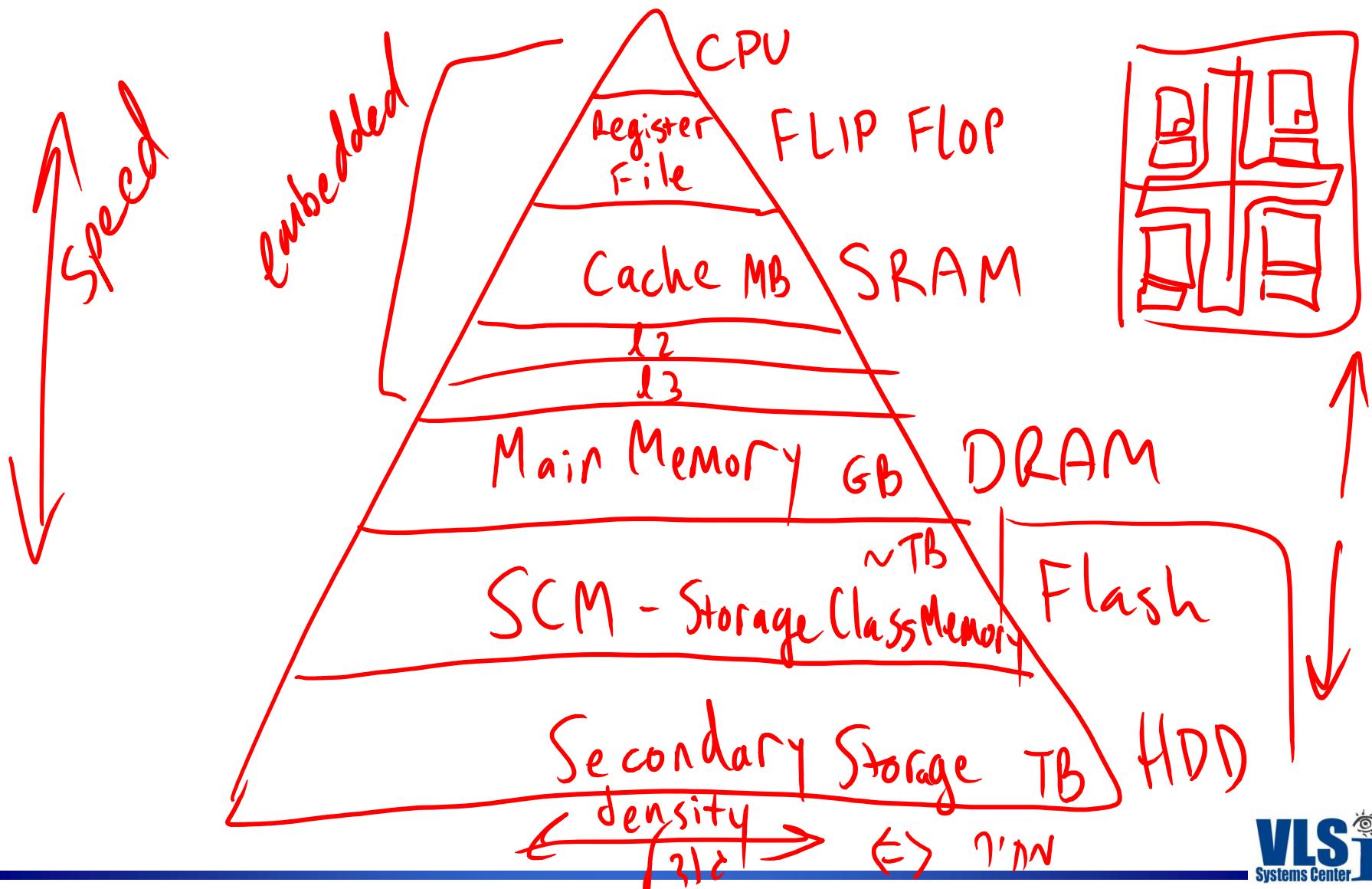
11.5 DRAM

Sequential Logic



Memory Hierarchy

Volatility



11.1

11.1 The Latch

11.2 The Flip Flop

11.3 Read Only Memory

11.4 SRAM

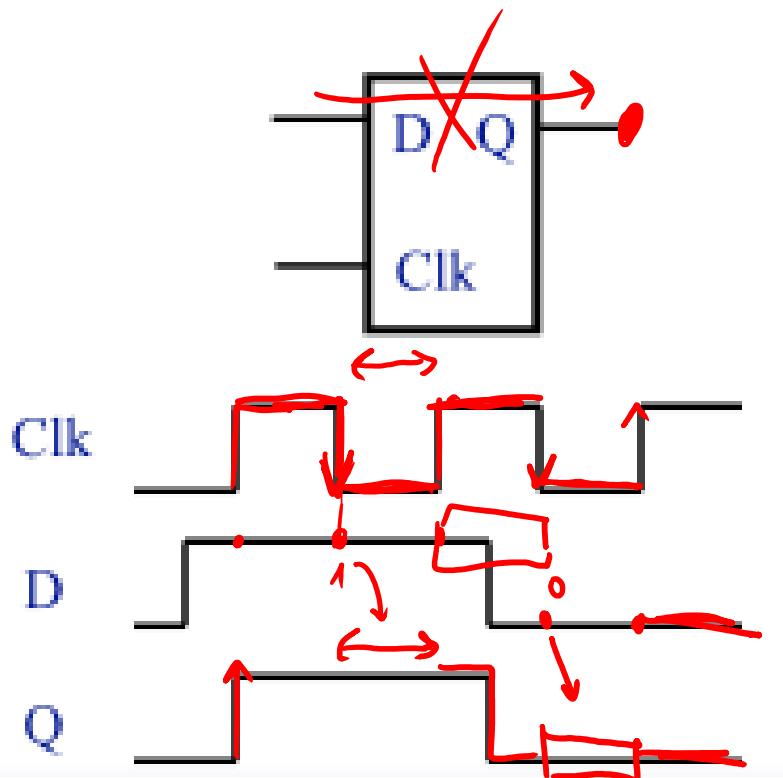
11.5 DRAM

The basic sequential timing element is the

LATCH

Transparent Latch

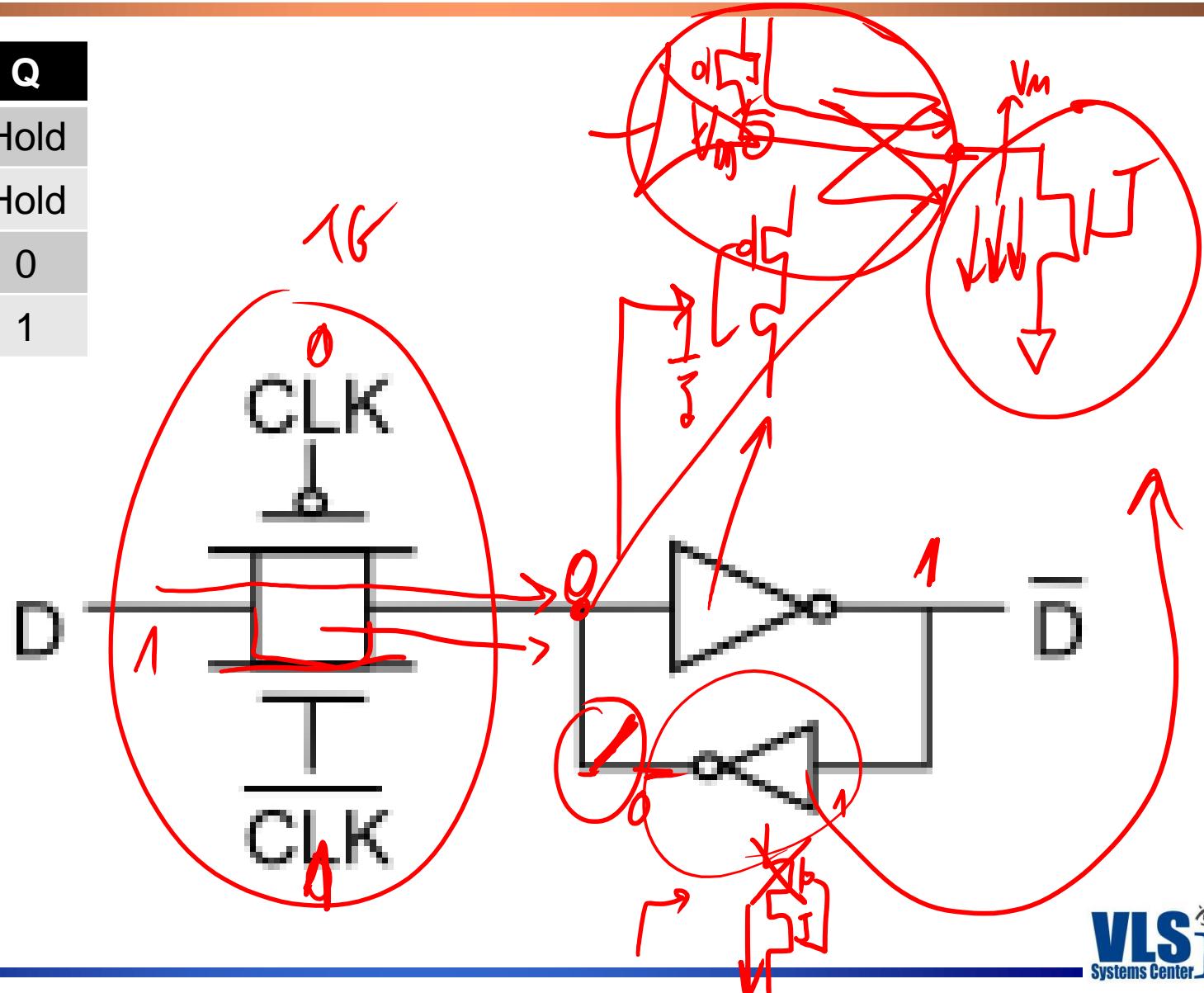
- Latch: level-sensitive
clock is low - hold mode
clock is high - transparent



Clk	D	Q
0	0	Hold
0	1	Hold
1	0	0
1	1	1

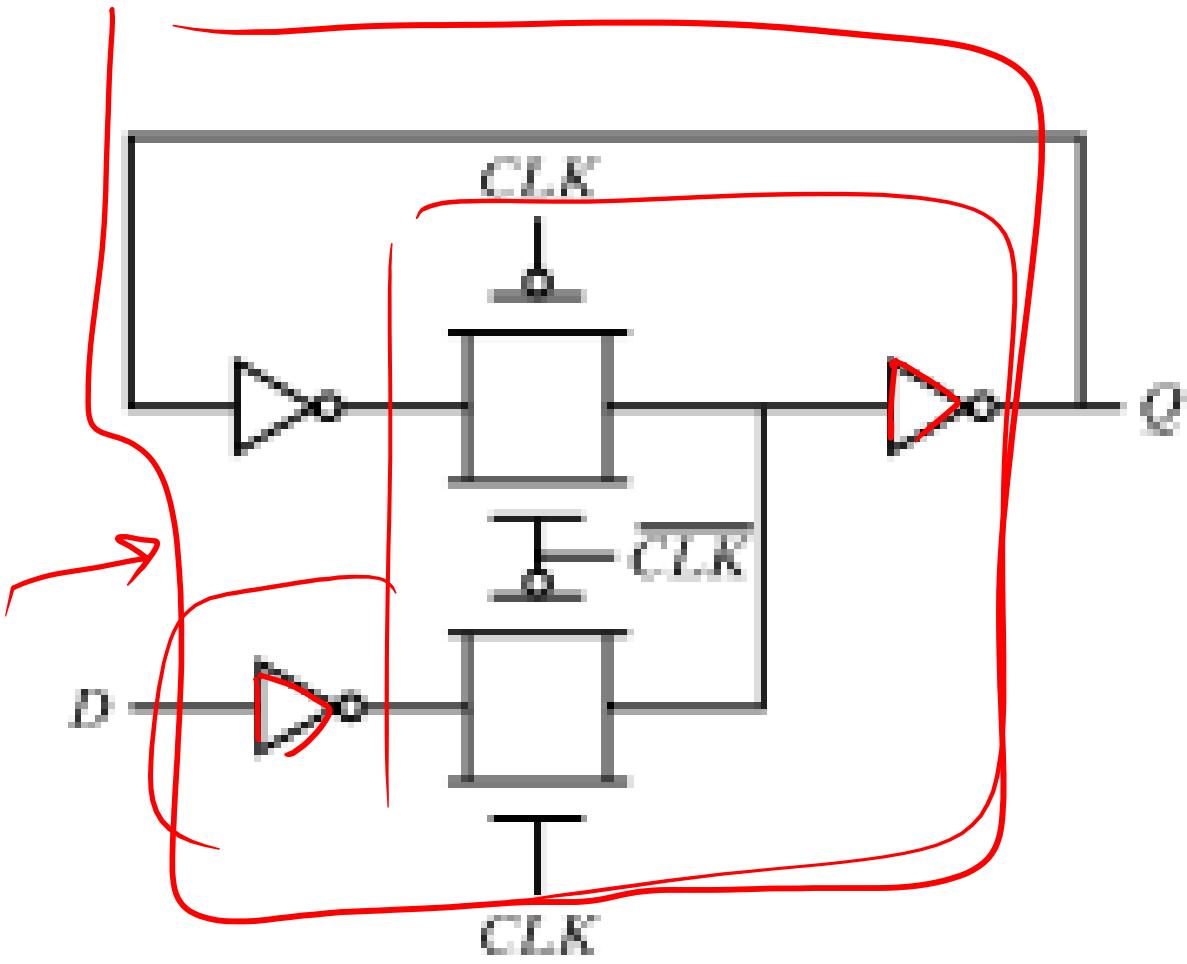
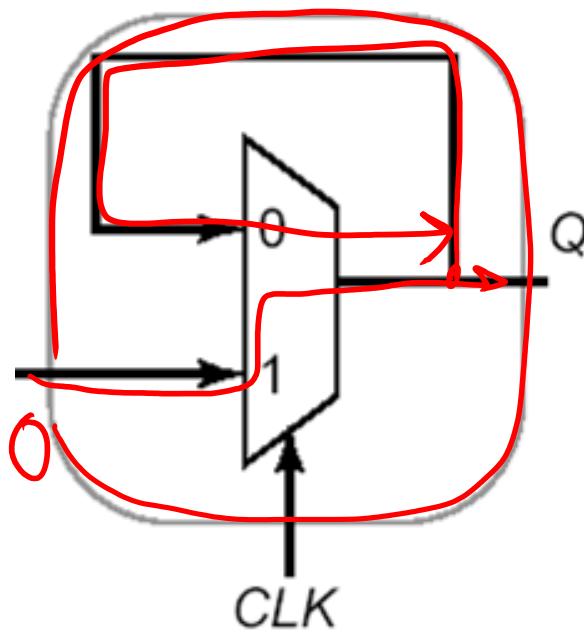
Basic Static Latch

Clk	D	Q
0	0	Hold
0	1	Hold
1	0	0
1	1	1

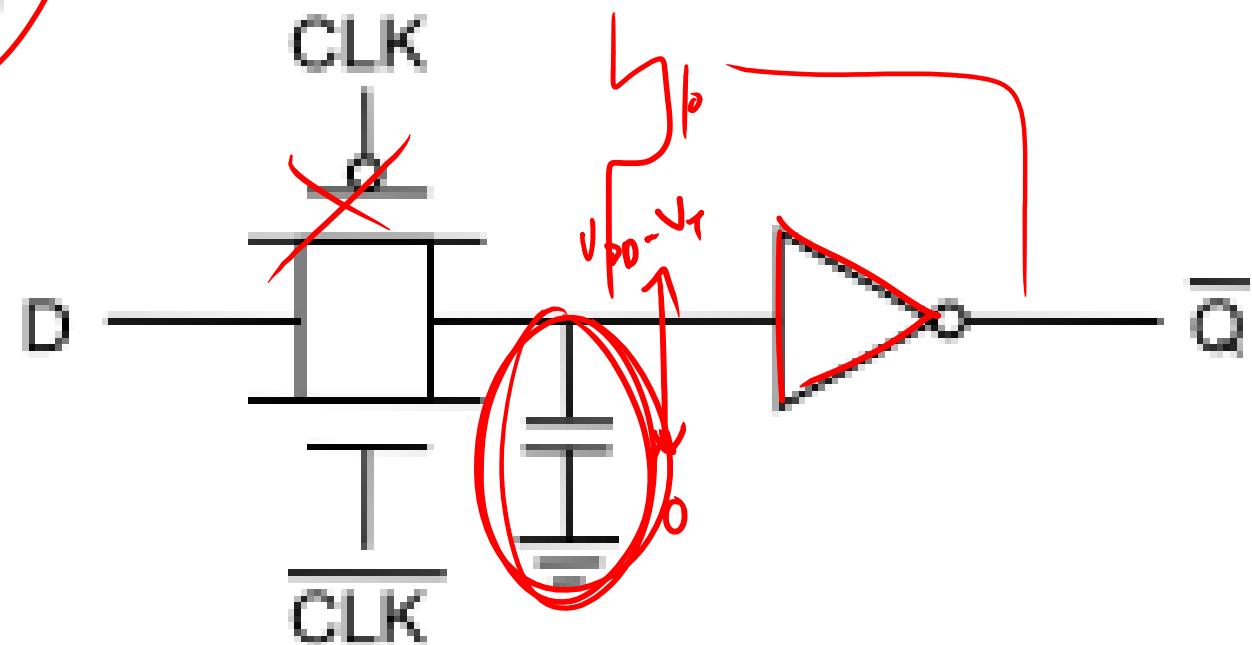
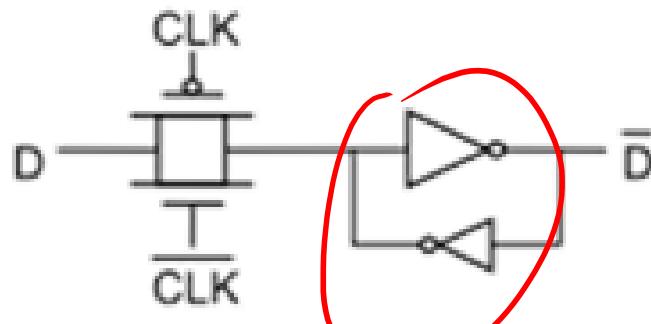


Feedback Mux Latch

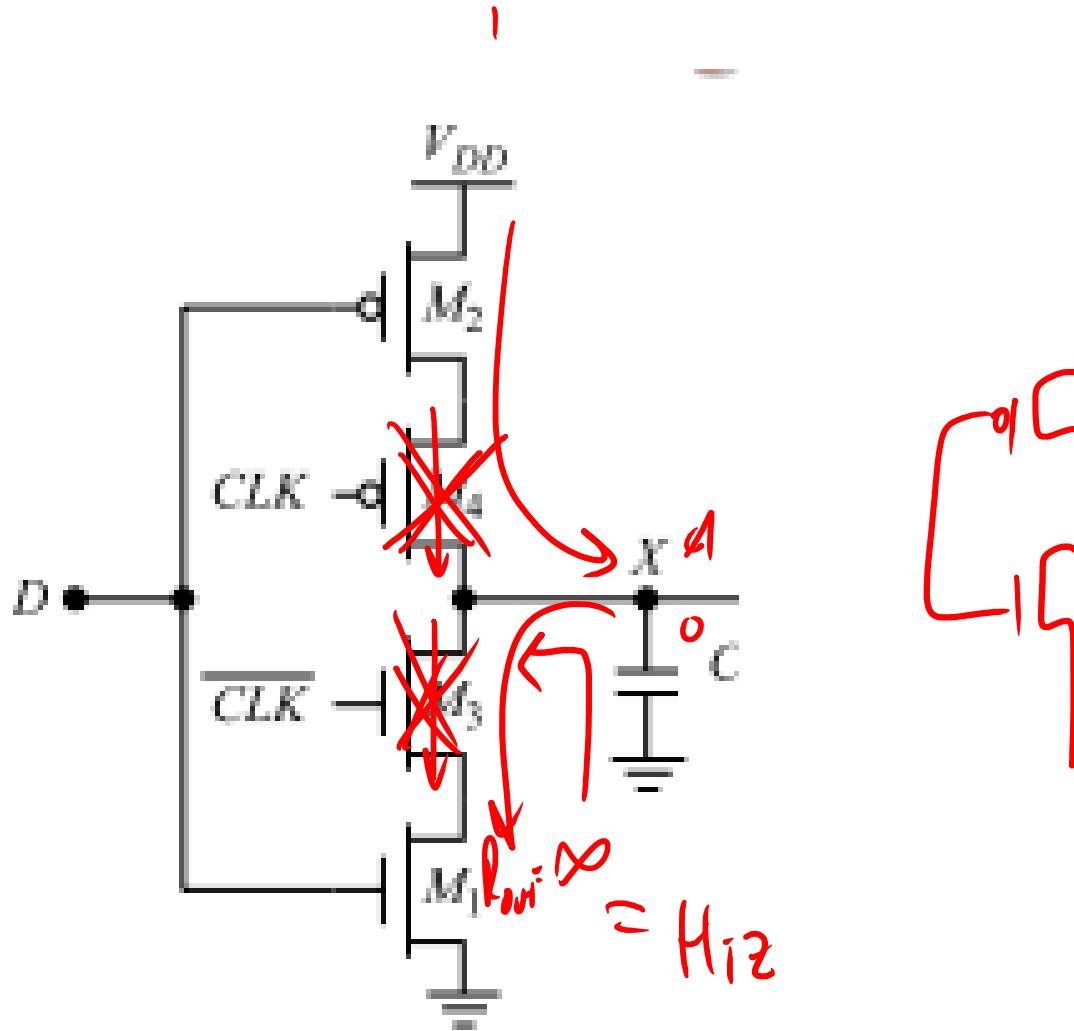
C _{lk}	D	Q
0	0	Hold
0	1	Hold
1	0	0
1	1	1

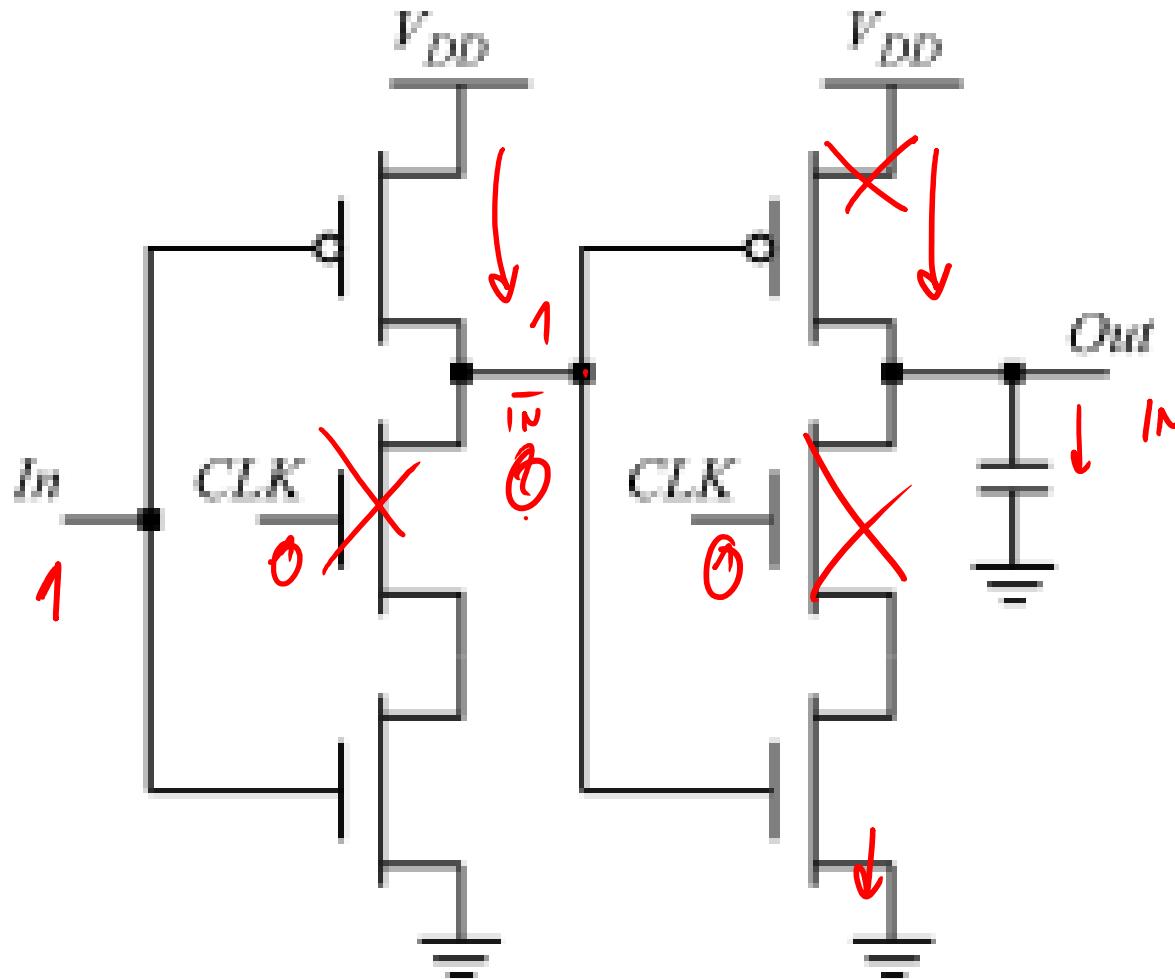


Simple Dynamic Latch



C²MOS





11.2

11.1 The Latch

11.2 The Flip Flop

11.3 Read Only Memory

11.4 SRAM

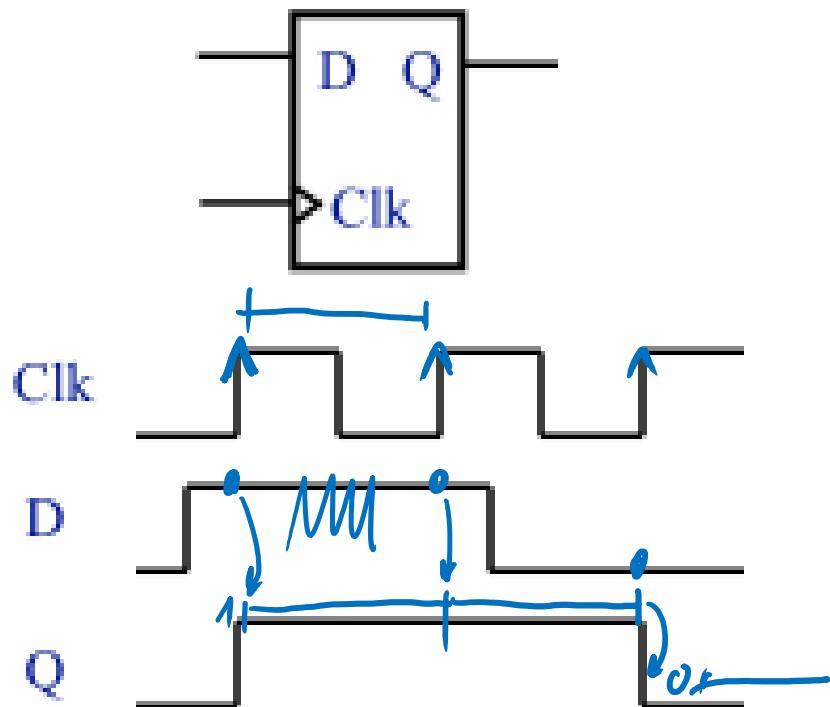
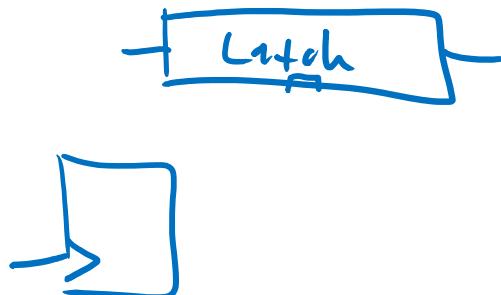
11.5 DRAM

The most important timing element in synchronous systems is the

FLIP FLOP

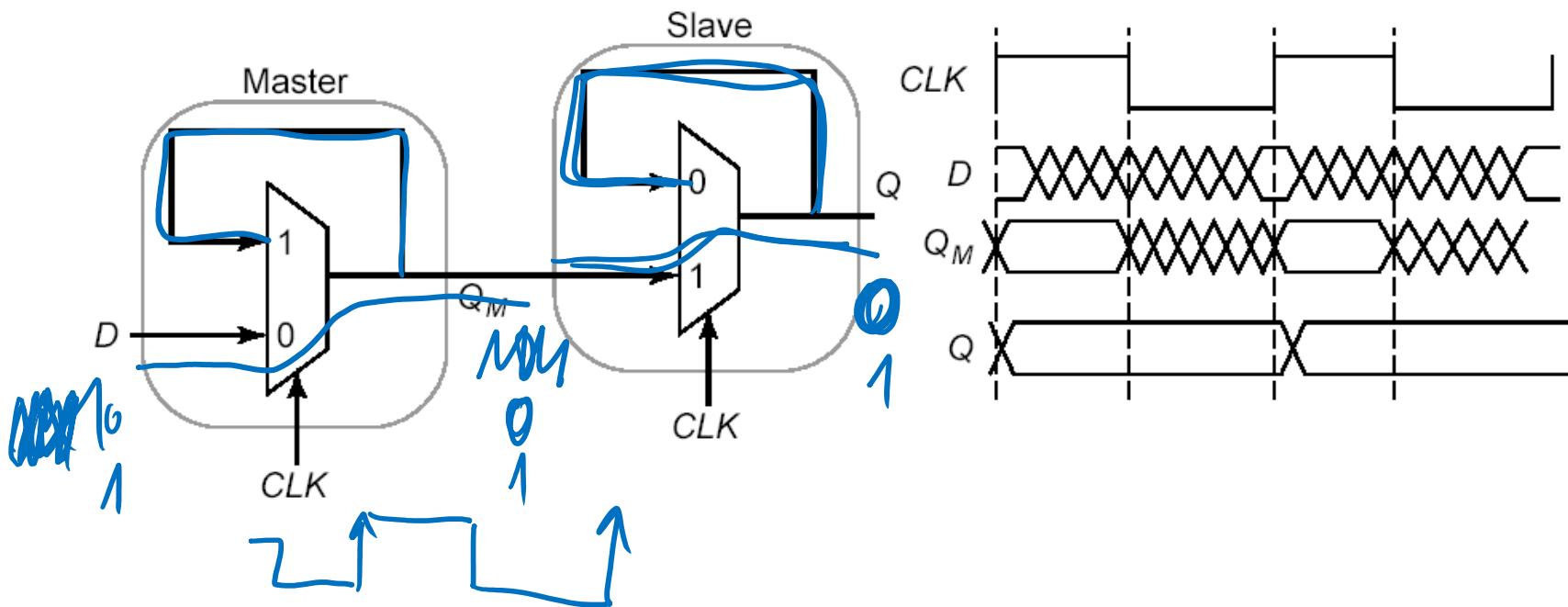
Flip Flop = Register

- ♦ Register: edge-triggered stores data when clock rises



Clk	D	Q
0 → 1	0	0
0 → 1	1	1
0	X	Hold
1	X	Hold

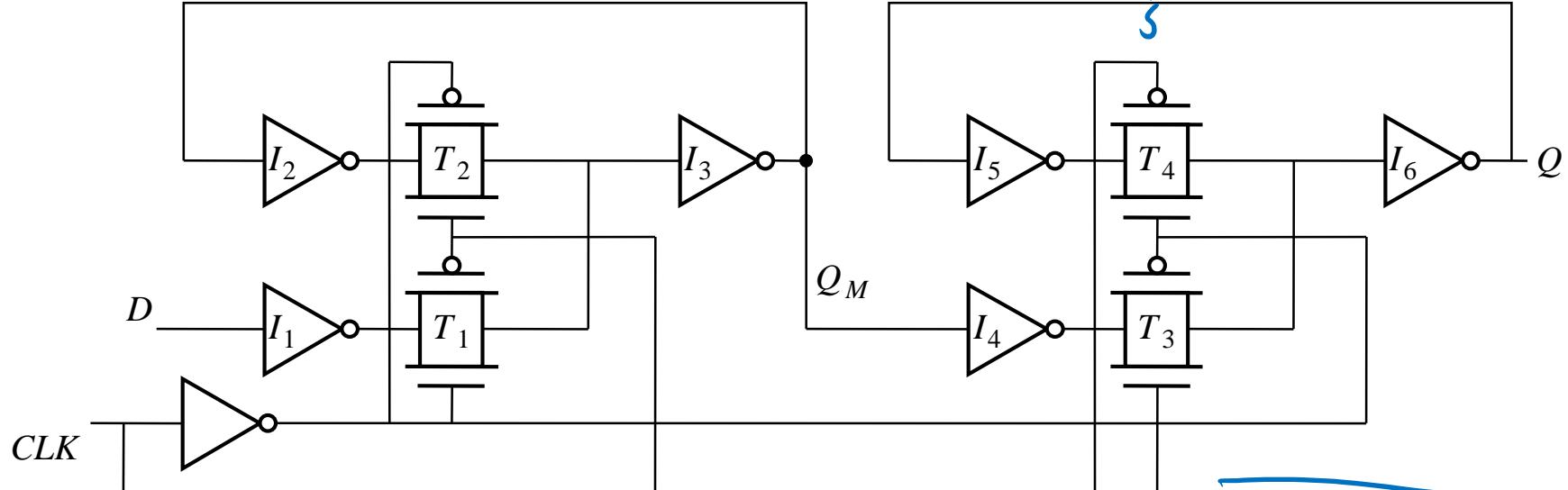
Master-Slave (Edge-Triggered) Register



Two opposite latches trigger on edge
Also called master-slave latch pair

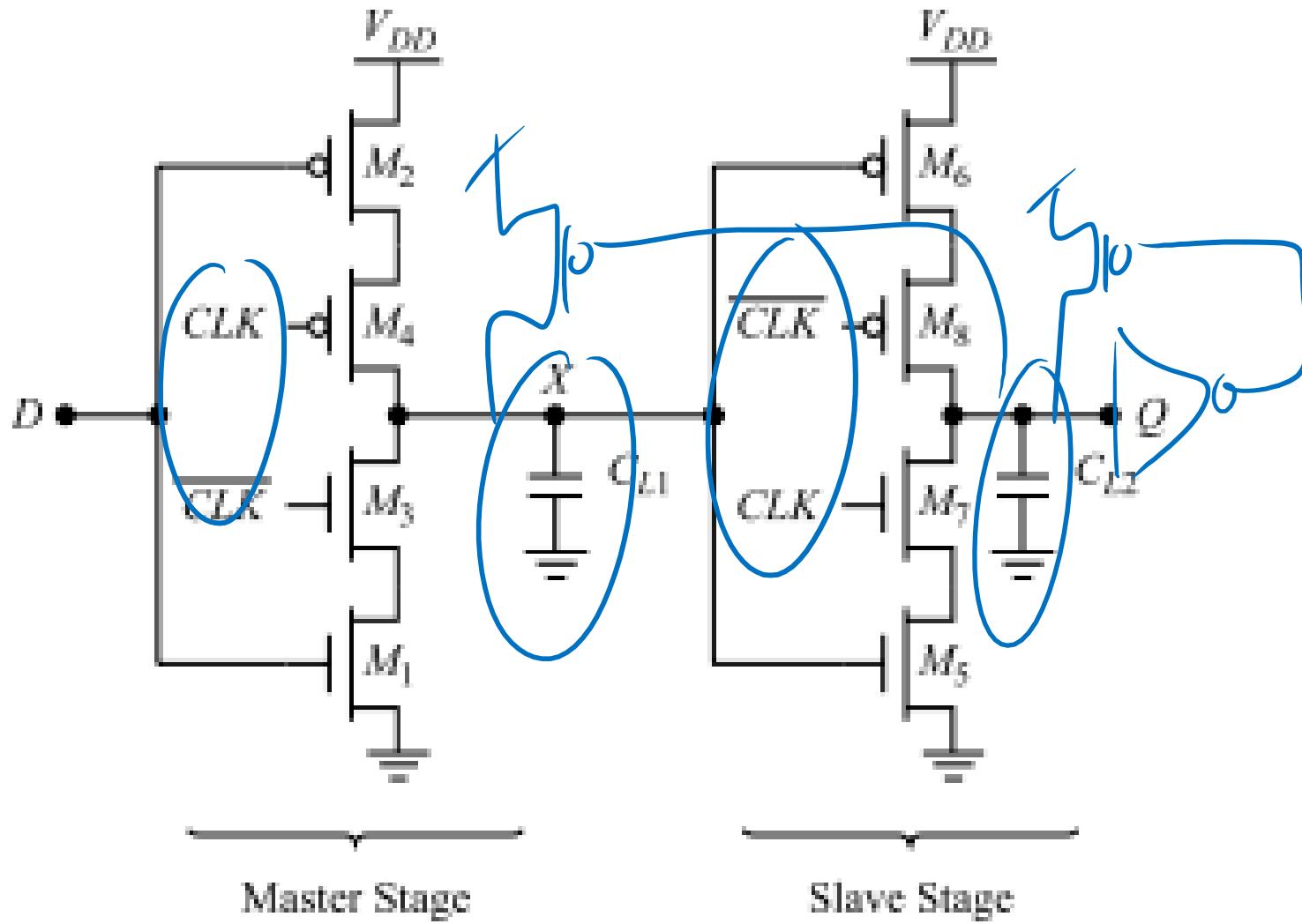
Master-Slave Register

Multiplexer-based latch pair



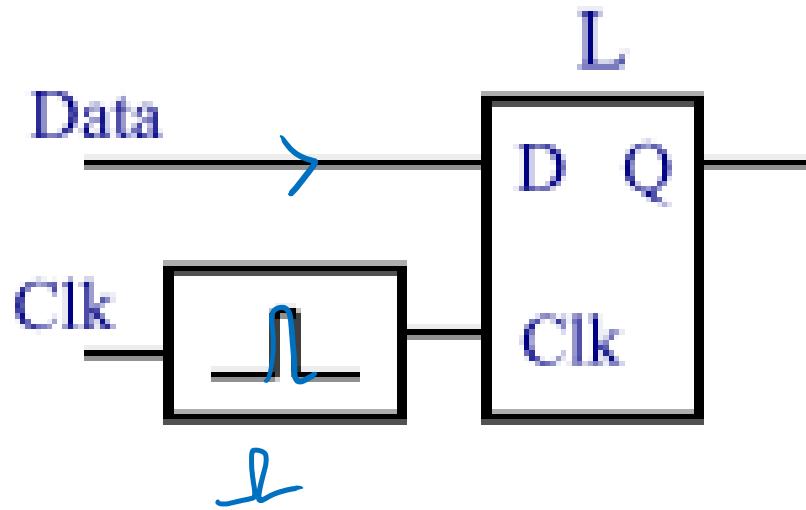
Clock load – 8 transistors

C2MOS Register



Pulse Triggered Register

Pulse-Triggered Latch



11.3

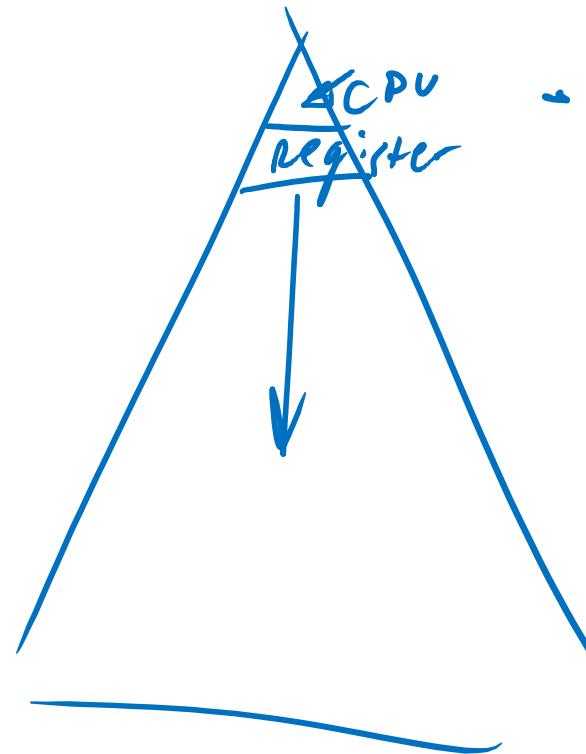
11.1 The Latch

11.2 The Flip Flop

11.3 Read Only Memory

11.4 SRAM

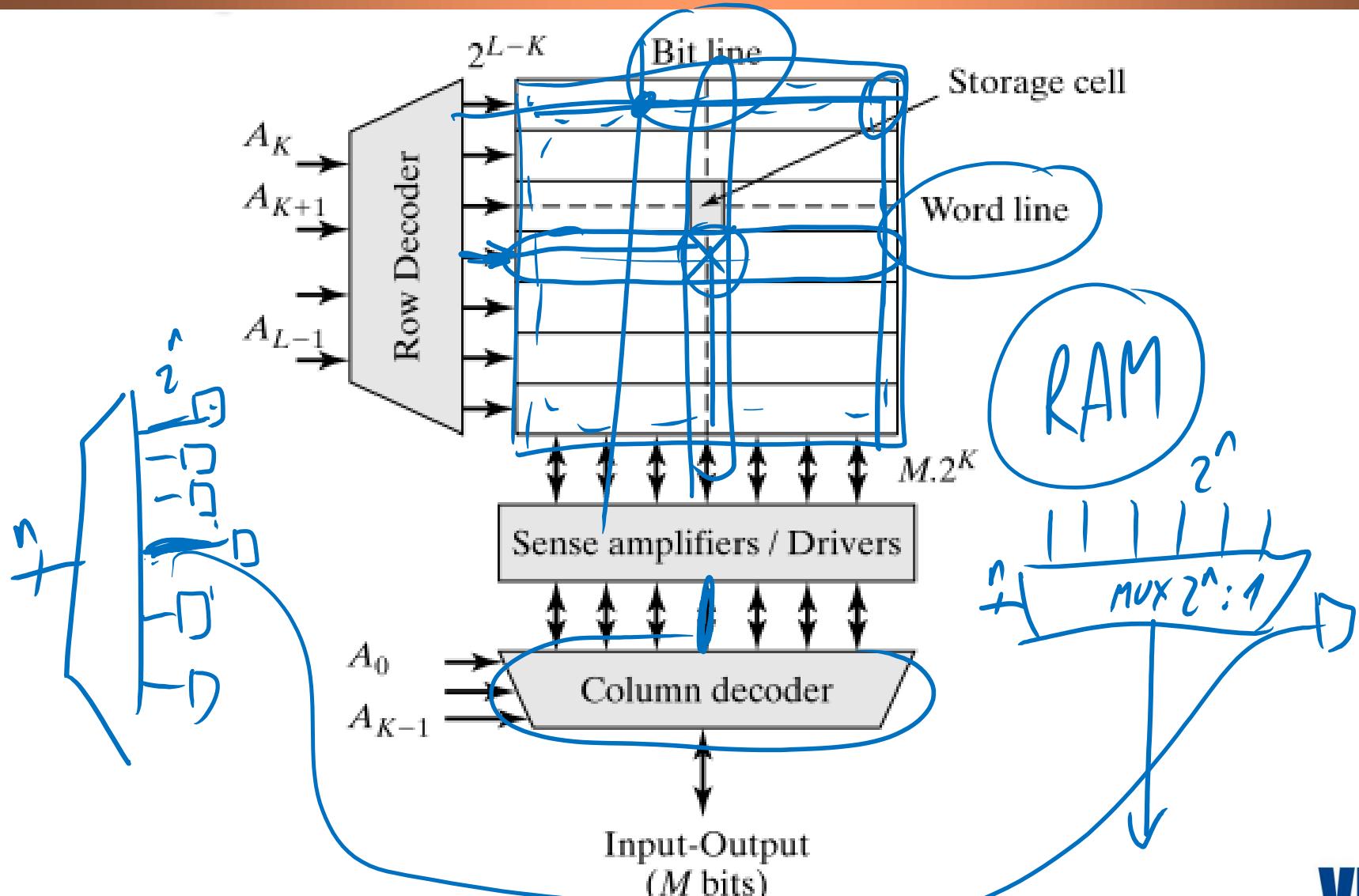
11.5 DRAM



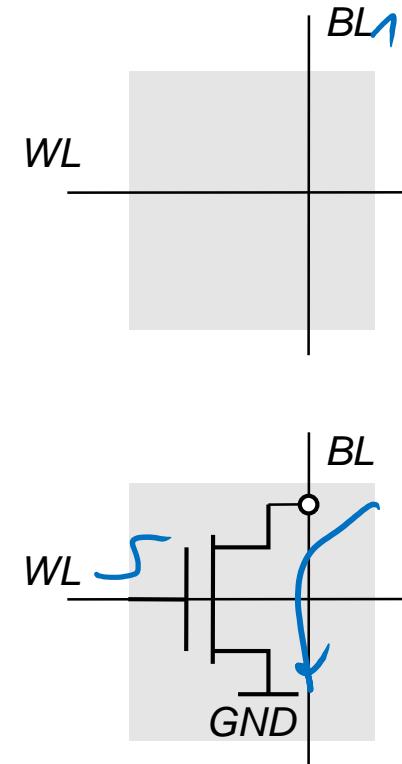
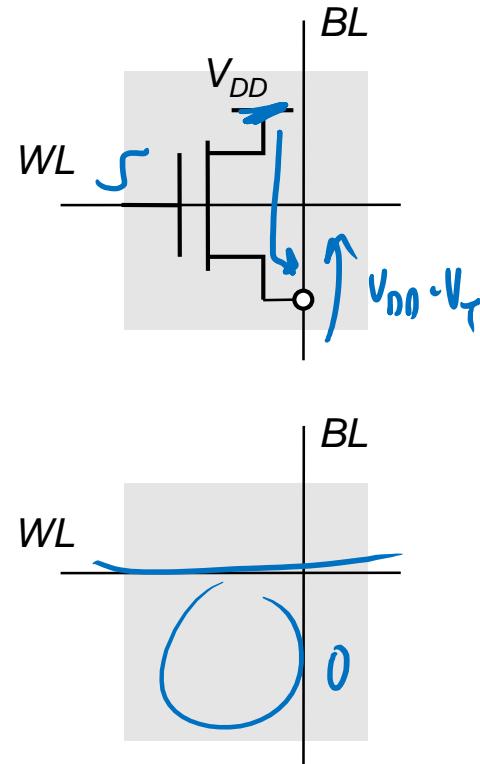
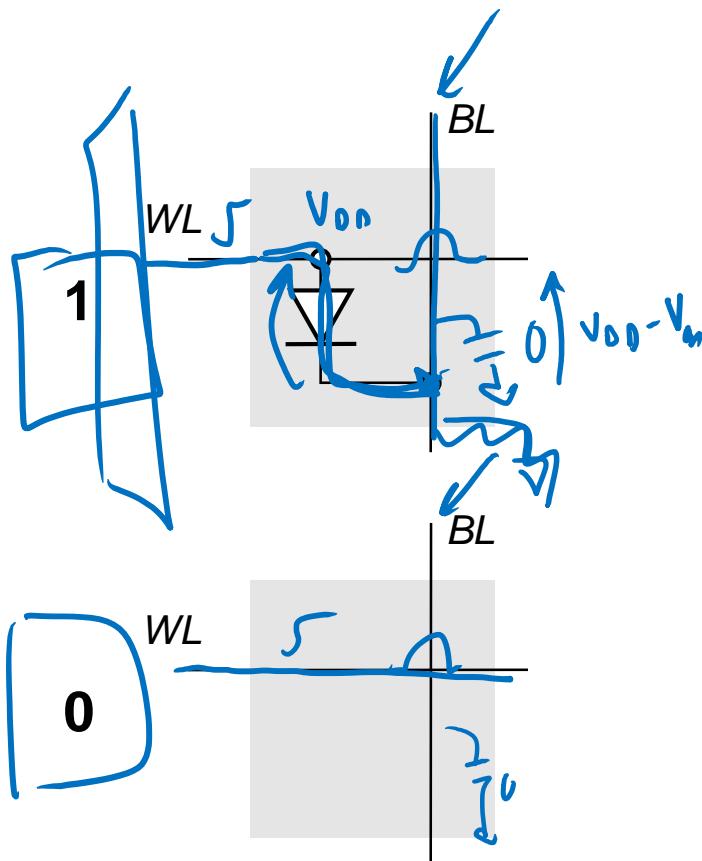
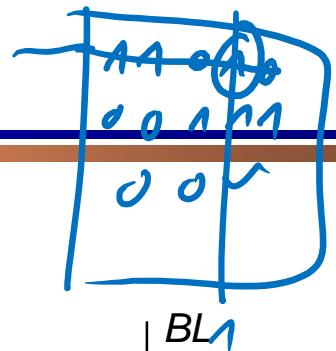
Now we are ready to look at the basic memory array:

READ ONLY MEMORY

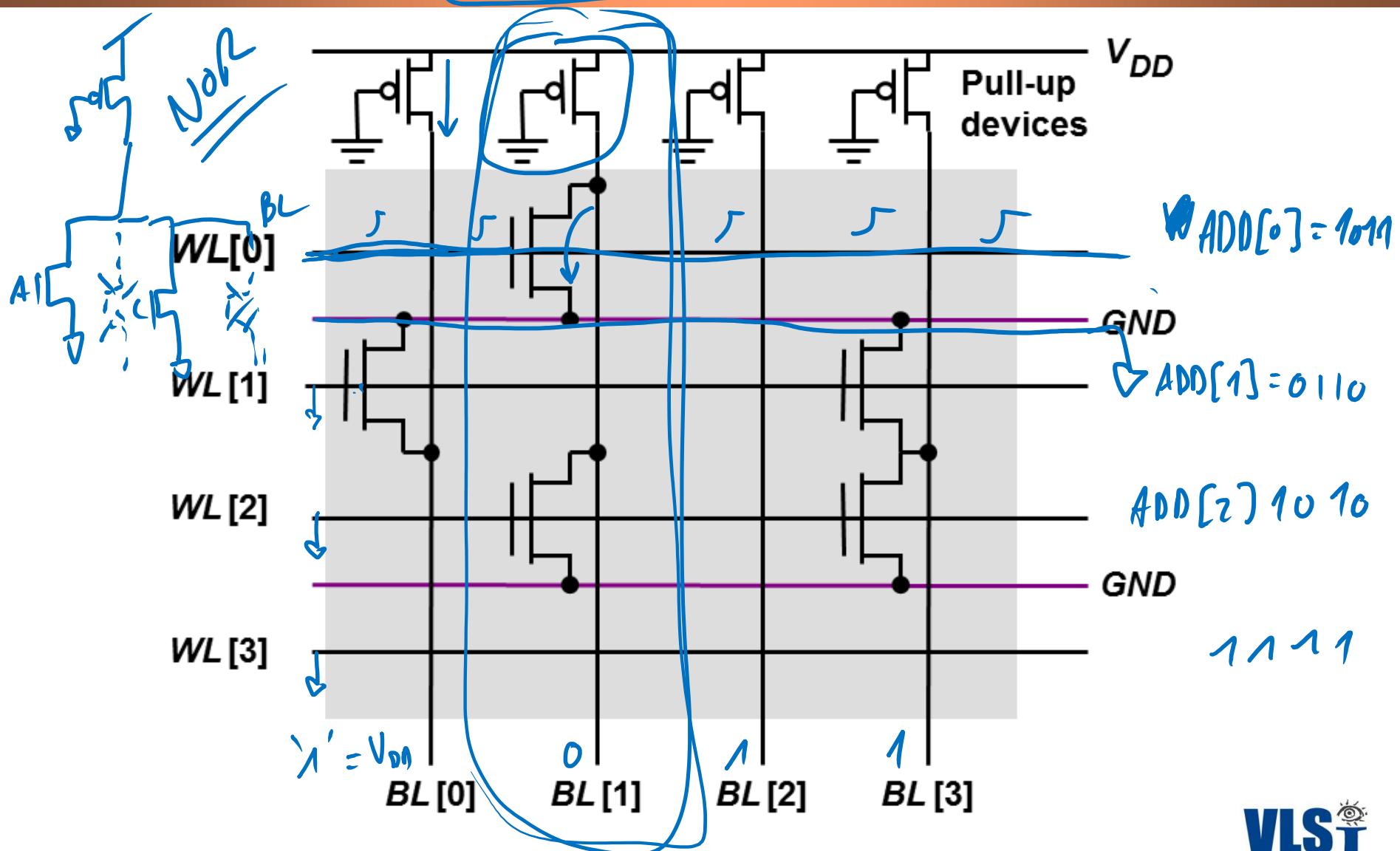
Memory Architecture



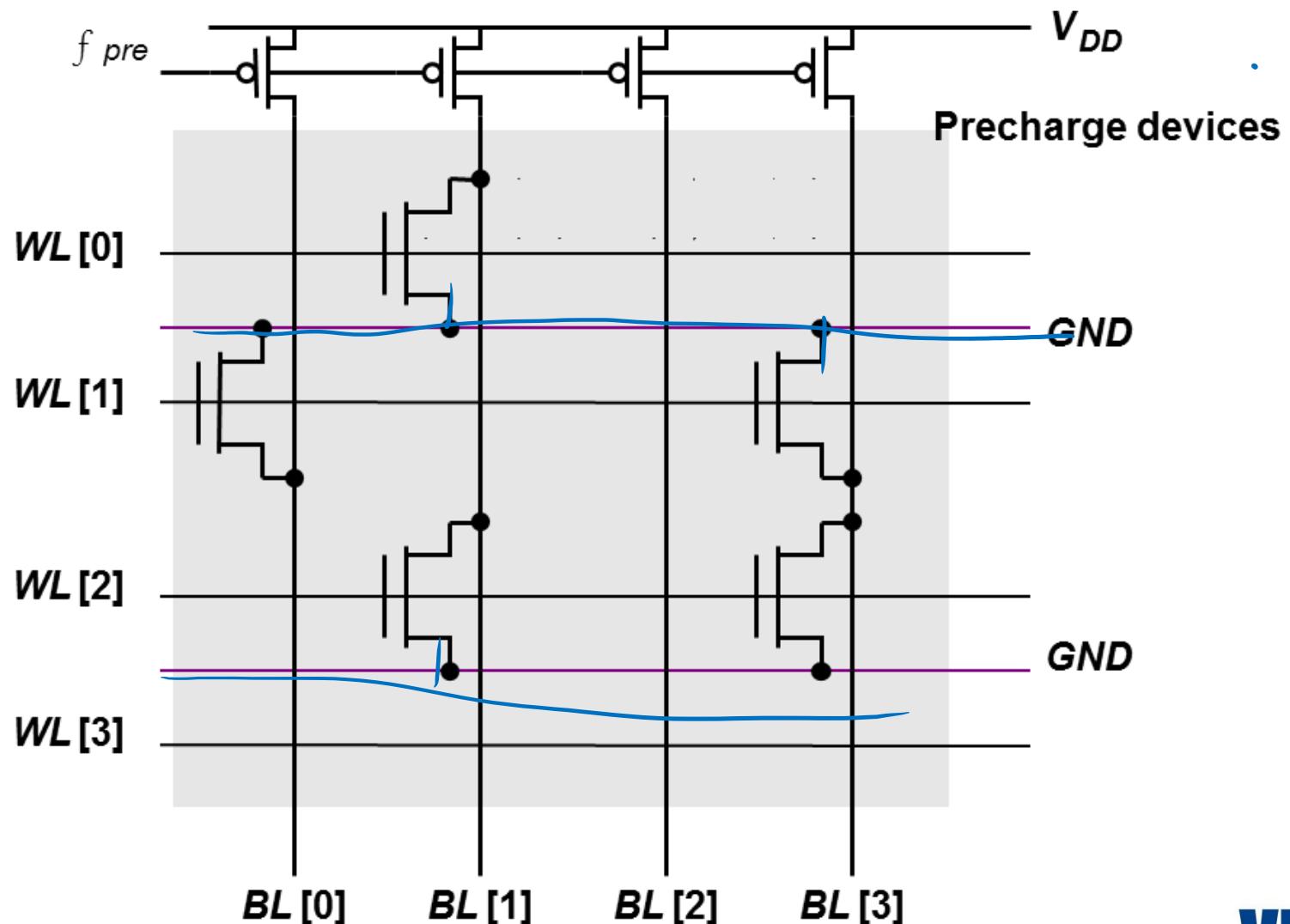
Read-Only Memory Cells



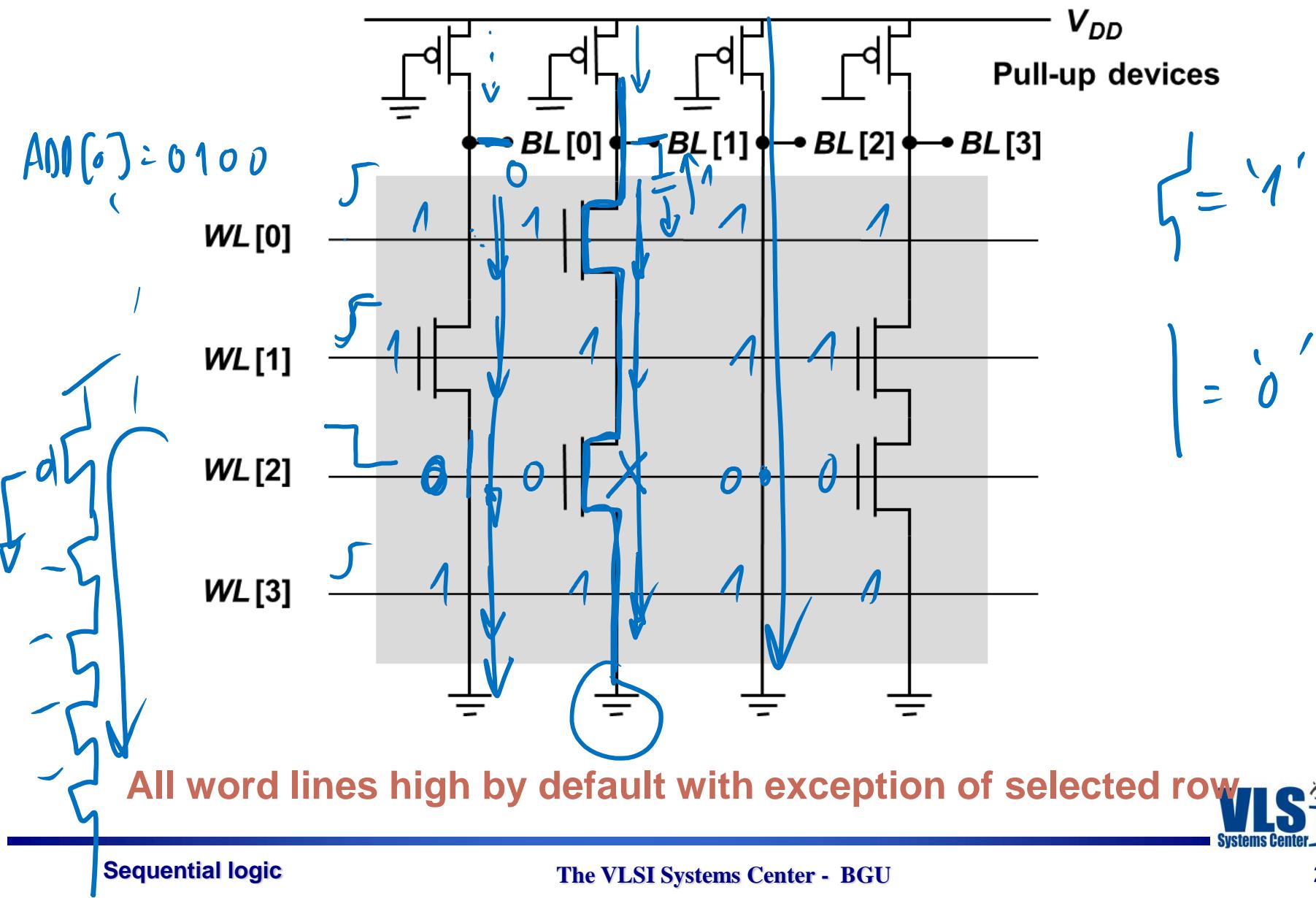
MOS NOR ROM



Precharged MOS NOR ROM



MOS NAND ROM



11.4

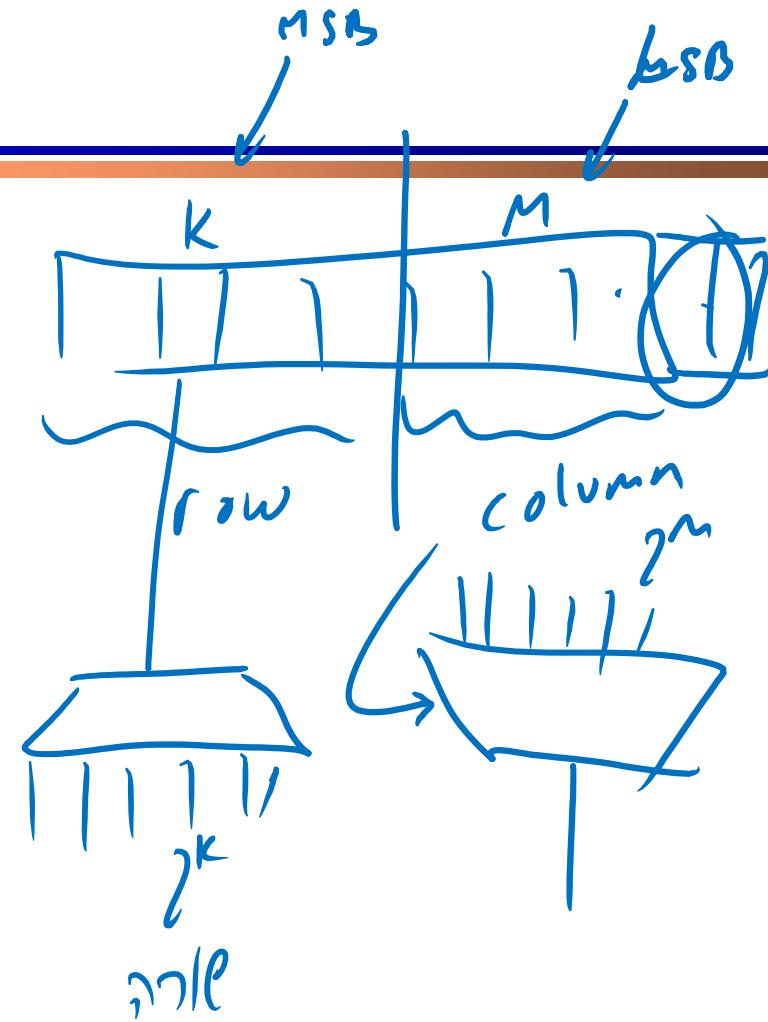
11.1 The Latch

11.2 The Flip Flop

11.3 Read Only Memory

11.4 SRAM

11.5 DRAM



Most embedded memories are implemented with

STATIC RANDOM ACCESS MEMORY

Random Access Memories

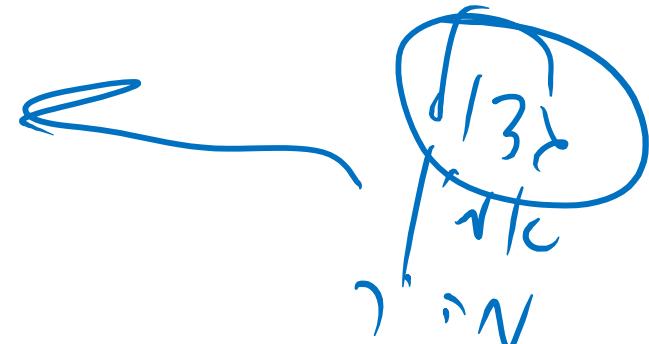
STATIC (SRAM)

Data stored as long as supply is applied

Larger (6 transistors/cell)

Fast

Differential (usually)



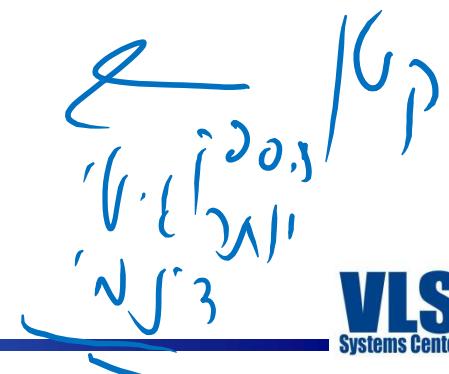
DYNAMIC (DRAM)

Periodic refresh required

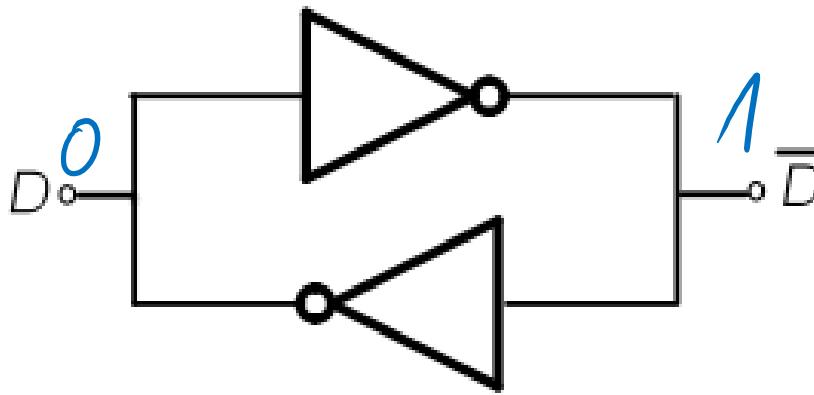
Smaller (1-3 transistors/cell)

Slower

Single Ended

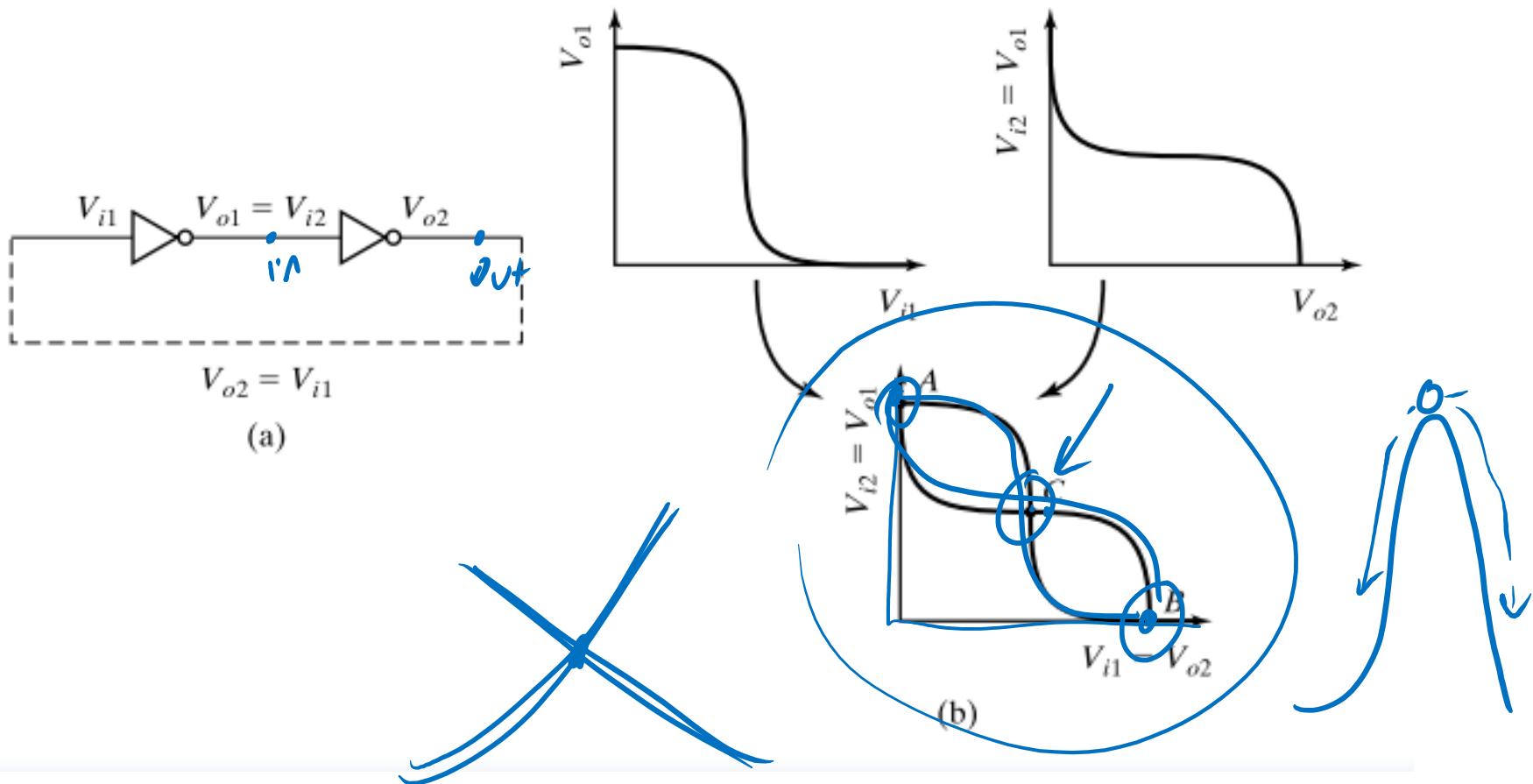


Basic Static Memory Element

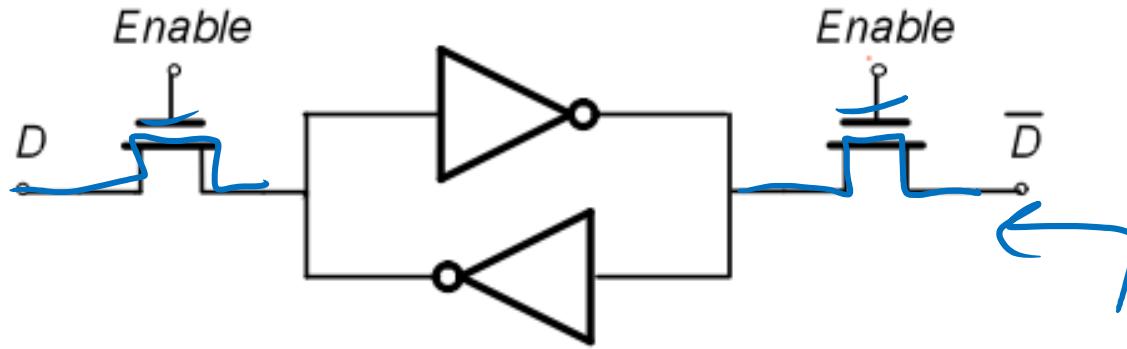


- If D is high, D_b will be driven low
 - Which makes D stay high
- Positive feedback

Positive Feedback: Bi-Stability

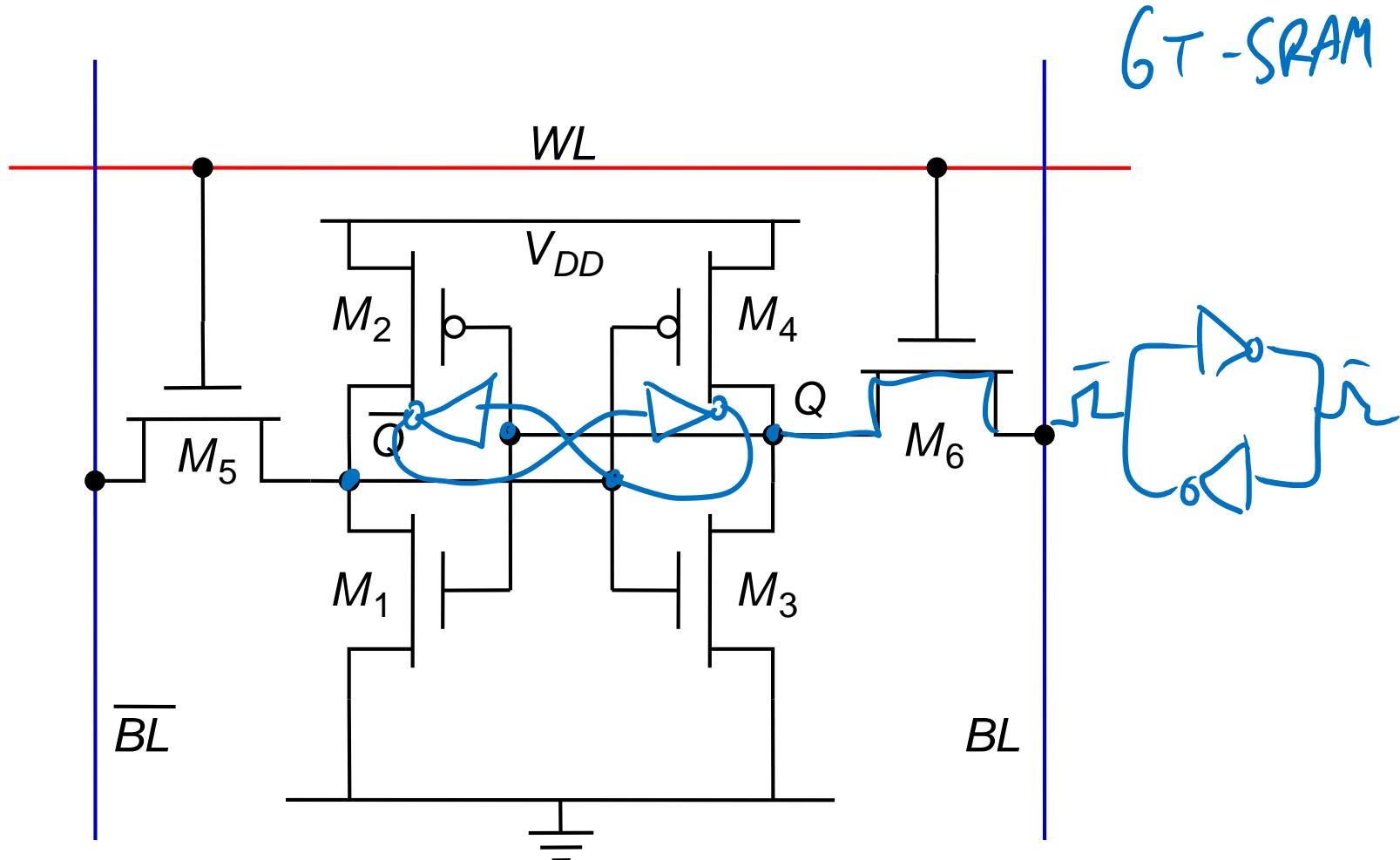


Memory Cell

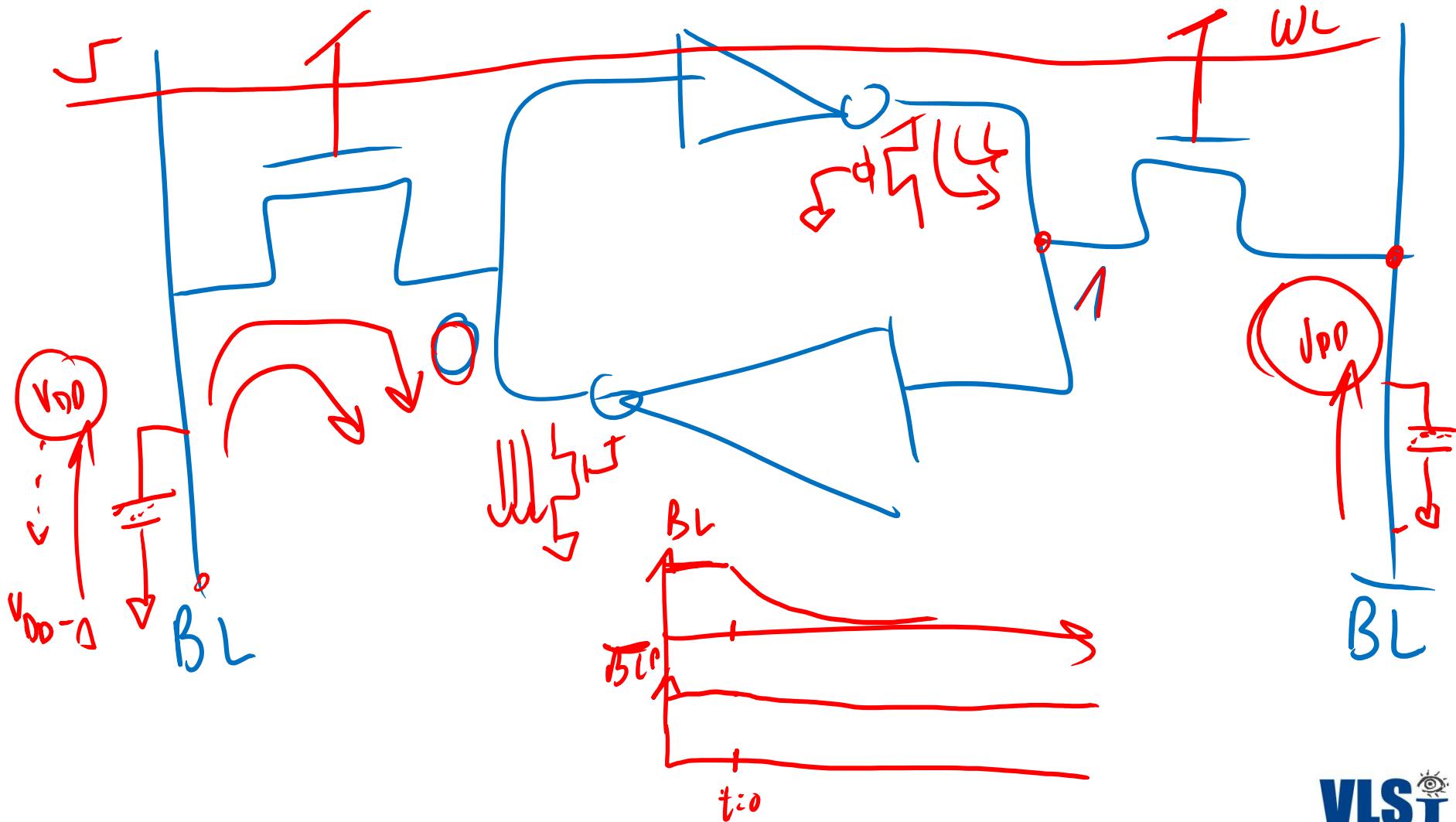


Complementary data values are written (read) from two sides

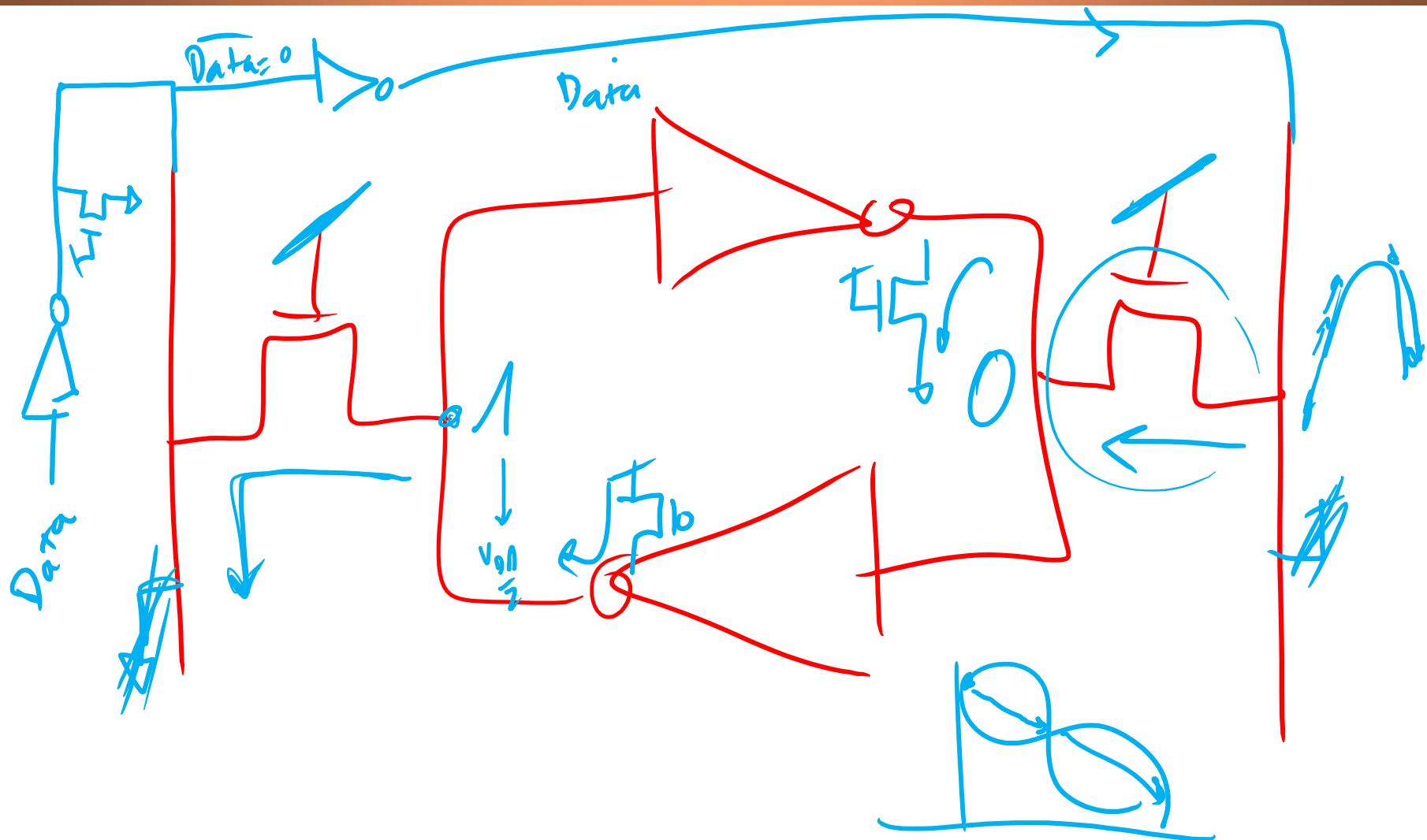
6-transistor CMOS SRAM Cell



SRAM Operation - Read



SRAM Operation - Write



11.5

11.1 The Latch

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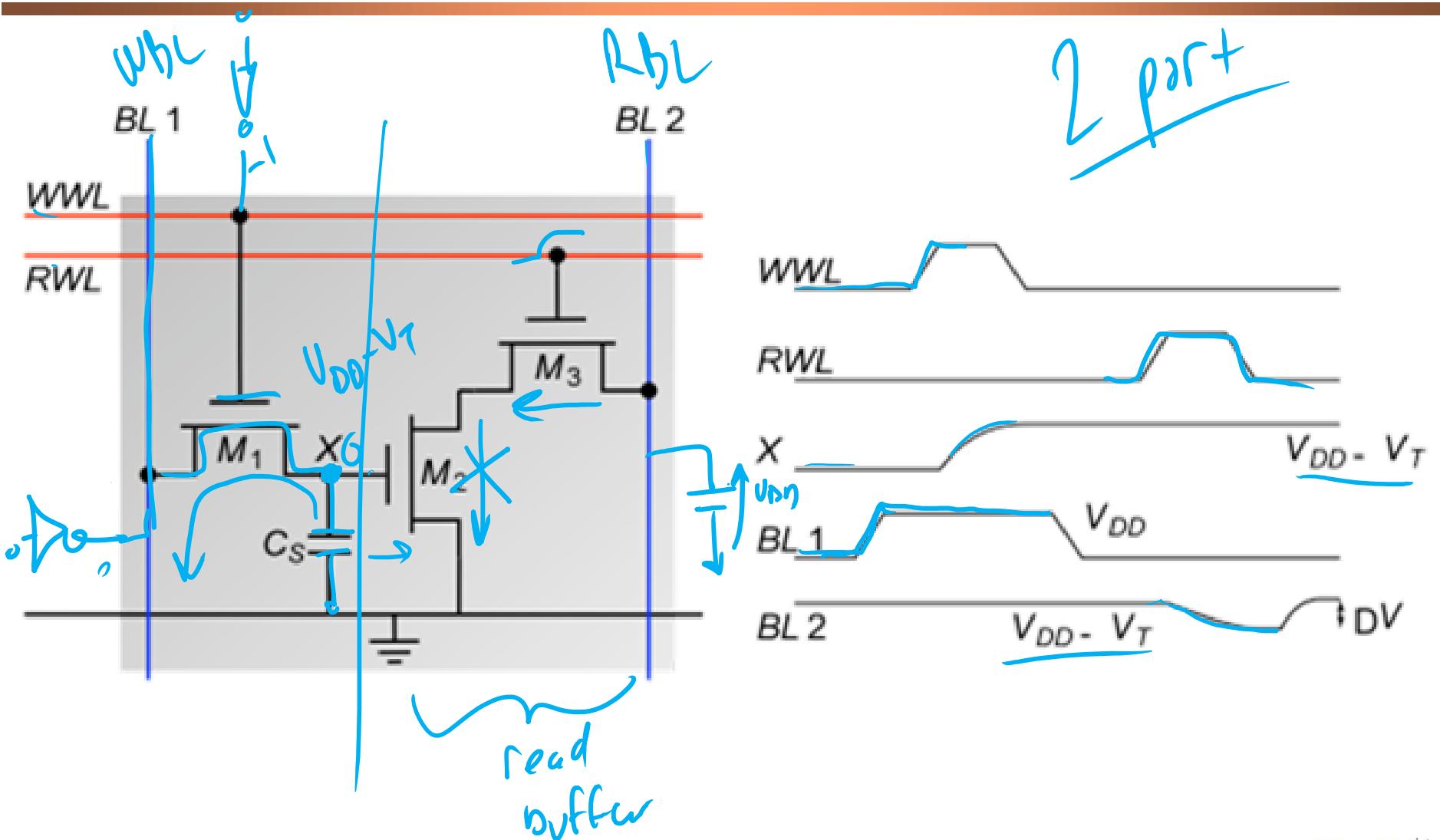
11.5 DRAM

How about reducing the number of transistors to achieve high density...

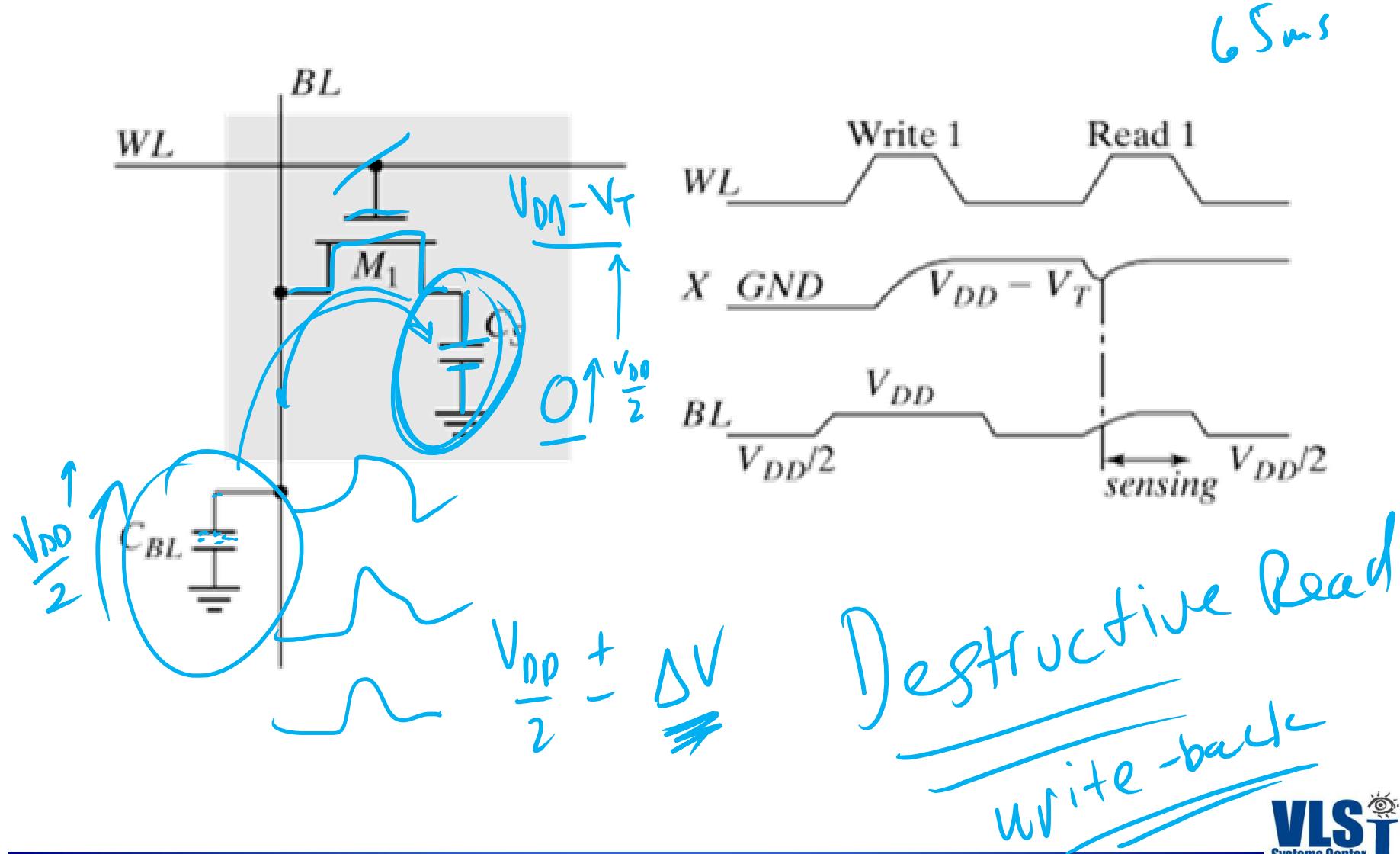
DYNAMIC RANDOM ACCESS MEMORY



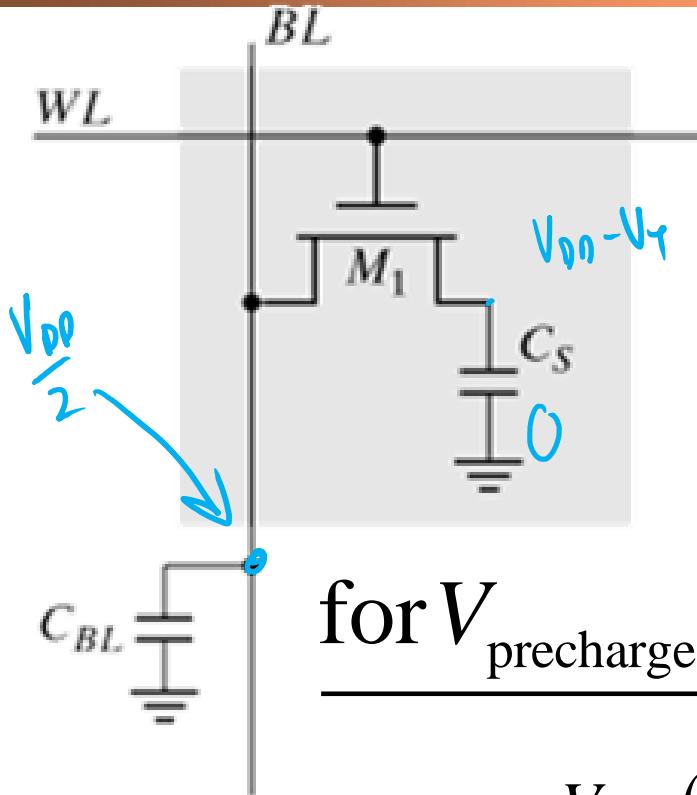
3-Transistor DRAM Cell



1-Transistor DRAM Cell



1-Transistor DRAM Cell



$$Q_{initial} = V_{\text{precharge}} C_{BL} + V_S C_S$$

$$Q_{final} = V_{\text{final}} (C_{BL} + C_S)$$

for $V_{\text{precharge}} = \underline{\underline{V_{DD}/2}}$:

$$V_{\text{final}}('0') = \frac{V_{DD}}{2} \frac{C_{BL}}{(C_{BL} + C_S)}$$

$$V_{\text{final}}('1') = \frac{(V_{DD} - V_T)C_S + 0.5V_{DD}C_{BL}}{(C_{BL} + C_S)}$$